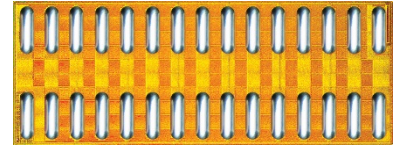


EPC2022_55 – Enhancement-Mode Power Transistor Preliminary Specification Sheet

Features:

- V_{DS} , 100 V
- Maximum $R_{DS(on)}$, 3.2 m Ω
- I_D , 90 A



EPC2022_55 eGaN® FETs are supplied in passivated die form with solder bars.
Die Size: 6.05 mm x 2.3 mm

Maximum Ratings			
V_{DS}	Drain-to-Source Voltage (Continuous)	100	V
	Drain-to-Source Voltage (up to 10,000 5ms pulses at 150°C)	120	
I_D	Continuous ($T_A = 25^\circ\text{C}$, $R_{\theta JA} = 2.5^\circ\text{C/W}$)	90	A
	Pulsed (25°C , $T_{PULSE} = 300 \mu\text{s}$)	290	
V_{GS}	Gate-to-Source Voltage	6	V
	Gate-to-Source Voltage	-4	
T_J	Operating Temperature	-55 to 150	°C
T_{STG}	Storage Temperature	-55 to 150	

Static Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise stated)						
PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
BV_{DSS}	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V}$, $I_D = 900 \mu\text{A}$	100			V
I_{DSS}	Drain Source Leakage	$V_{DS} = 80 \text{ V}$, $V_{GS} = 0 \text{ V}$, $T_J = 25^\circ\text{C}$		100	700	μA
		$V_{DS} = 80 \text{ V}$, $V_{GS} = 0 \text{ V}$, $T_J = -55^\circ\text{C}$		25	700	μA
I_{GSS}	Gate-to-Source Forward Leakage	$V_{GS} = 5 \text{ V}$, $T_J = 25^\circ\text{C}$		1	9	mA
		$V_{GS} = 5 \text{ V}$, $T_J = -55^\circ\text{C}$		0.25	9	mA
	Gate-to-Source Reverse Leakage	$V_{GS} = -4 \text{ V}$, $T_J = 25^\circ\text{C}$		0.1	0.7	mA
		$V_{GS} = -4 \text{ V}$, $T_J = -55^\circ\text{C}$		0.025	0.7	mA
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 13 \text{ mA}$, $T_J = 25^\circ\text{C}$	0.8	1.4	2.5	V
		$V_{DS} = V_{GS}$, $I_D = 13 \text{ mA}$, $T_J = -55^\circ\text{C}$	0.8	1.6	2.5	V
$R_{DS(on)}$	Drain-Source On Resistance	$V_{GS} = 5 \text{ V}$, $I_D = 25 \text{ A}$, $T_J = 25^\circ\text{C}$		2.4	3.2	m Ω
		$V_{GS} = 5 \text{ V}$, $I_D = 25 \text{ A}$, $T_J = -55^\circ\text{C}$		1.6	2.3	m Ω

All measurements were done with substrate shorted to source.

Thermal Characteristics			
		TYP	UNIT
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.4	°C/W
$R_{\theta JB}$	Thermal Resistance, Junction to Board	1.1	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1)	42	°C/W

Note 1: $R_{\theta JA}$ is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board.
 See http://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf for details.

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PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
C_{ISS}	Input Capacitance	$V_{DS} = 50\text{ V}, V_{GS} = 0\text{ V}$		1400	1680	pF
C_{RSS}	Reverse Transfer			7		
C_{OSS}	Output Capacitance			840	1260	
$C_{OSS(ER)}$	Effective Output Capacitance, Energy Related (Note 2)	$V_{DS} = 0\text{ to }50\text{ V}, V_{GS} = 0\text{ V}$		1090		
$C_{OSS(TR)}$	Effective Output Capacitance, Time Related (Note 3)			1410		
R_G	Gate Resistance			0.3		Ω
Q_G	Total Gate Charge	$V_{DS} = 50\text{ V}, V_{GS} = 5\text{ V}, I_D = 25\text{ A}$		13	16	nC
Q_{GS}	Gate-to-Source Charge	$V_{DS} = 50\text{ V}, I_D = 25\text{ A}$		3.4		
Q_{GD}	Gate-to-Drain Charge			2.4		
$Q_{G(TH)}$	Gate Charge at Threshold			2.1		
Q_{OSS}	Output Charge	$V_{DS} = 50\text{ V}, V_{GS} = 0\text{ V}$		71	107	
Q_{RR}	Source-Drain Recovery			0		

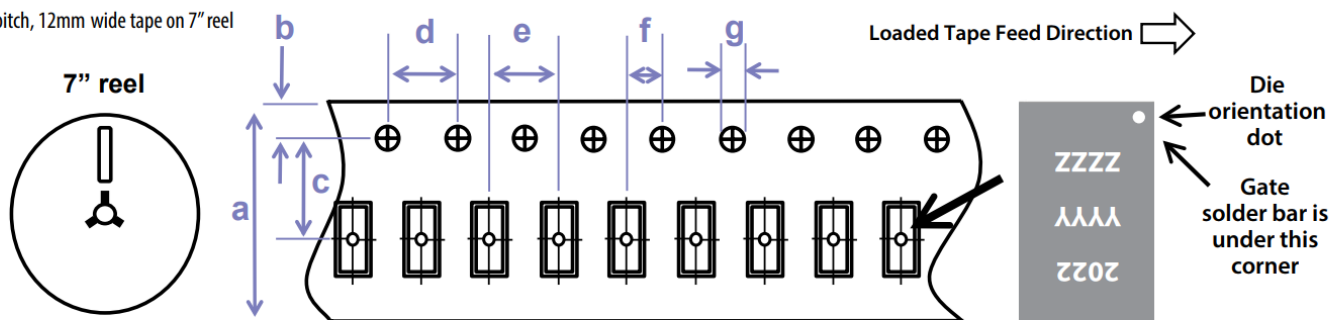
All measurements were done with substrate shorted to source.

Note 2: $C_{OSS(ER)}$ is a fixed capacitance that gives the same stored energy as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS}

Note 3: $C_{OSS(TR)}$ is a fixed capacitance that gives the same charging time as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS}

TAPE AND REEL CONFIGURATION

4mm pitch, 12mm wide tape on 7" reel



Die is placed into pocket
solder bar side down
(face side down)

Dimension (mm)	EPC2022 (note 1)		
	target	min	max
a	12.00	11.70	12.30
b	1.75	1.65	1.85
c (see note)	5.50	5.45	5.55
d	4.00	3.90	4.10
e	4.00	3.90	4.10
f (see note)	2.00	1.95	2.05
g	1.50	1.50	1.60

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/JEDEC industry standard.
Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

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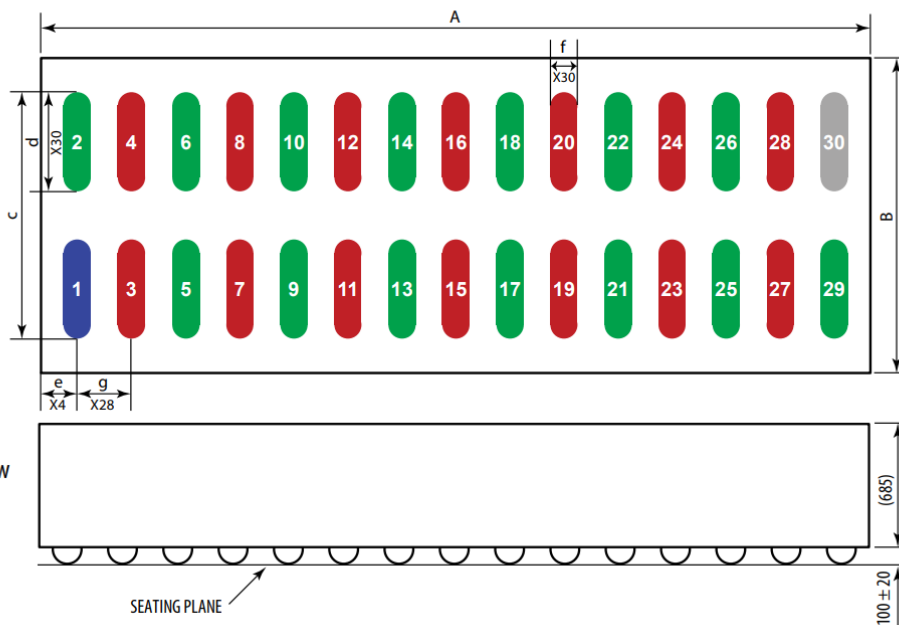
Preliminary Specification Sheet

DIE MARKINGS

Part Number	Laser Marking		
	Part # Marking Line 1	Lot_Date Code Marking Line 2	Lot_Date Code Marking Line 3
EPC2022	2022	YYYY	ZZZZ

DIE OUTLINE

Solder Bump View



DIM	Micrometers		
	MIN	Nominal	MAX
A	6020	6050	6080
B	2270	2300	2330
c	2047	2050	2053
d	717	720	723
e	210	225	240
f	195	200	205
g	400	400	400

Pad 1 is Gate

Pads 2,5,6,9,10,13,14,17,18,21,22, 25,26,29 are Source

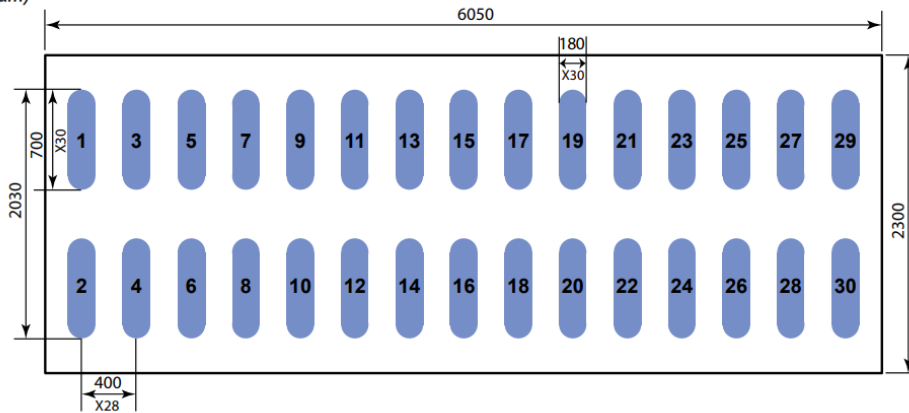
Pads 3,4,7,8,11,12,15,16,19,20,23, 24,27,28 are Drain

Pad 30 is Substrate

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RECOMMENDED LAND PATTERN

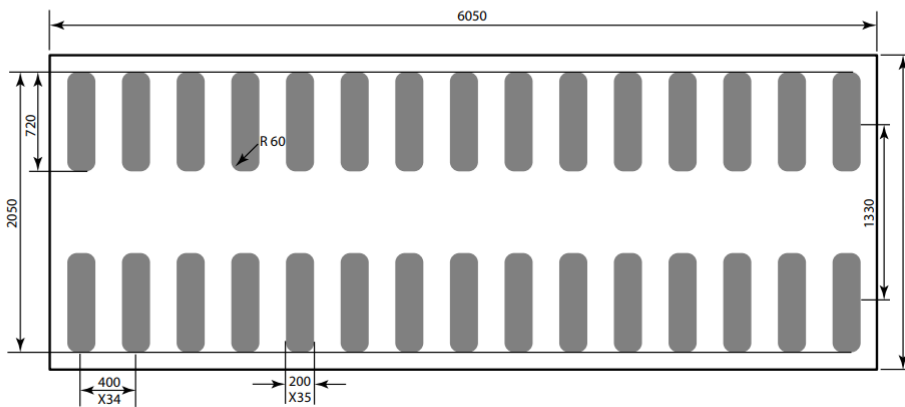
(units in μm)



Land pattern is solder mask defined
Solder mask opening is 180 μm
It is recommended to have on-Cu trace
PCB vias

RECOMMENDED STENCIL DRAWING

(units in μm)



Recommended stencil should be 4 mil (100 μm) thick, must be laser cut, openings per drawing.

Intended for use with SAC305 Type 3 solder, reference 88.5% metals content.

Additional assembly resources available at <http://epc-co.com/epc/DesignSupport/AssemblyBasics.aspx>

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